Annex B: Measurement Results

Tested Model: LJ8

Report Number: WSCT-ANAB-R&E250500034A-SAR

Measurement Report for Device, CHEEK, GSM 850, , Channel 190 (836.600MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	CHEEK,	GSM 850		836.600,	8.89	0.914	43.6
Head Simulating Liquid	0.00			190			

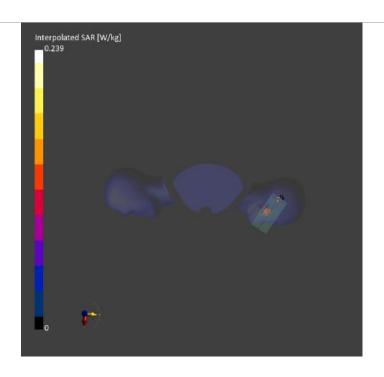
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-14	2025-03-14
psSAR1g [W/kg]	0.178	0.185
psSAR10g [W/kg]	0.118	0.137
Power Drift [dB]	0.01	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		92.0
Dist 3dB Peak [mm]		14.4



Measurement Report for Device, BACK, GSM 850, Channel 190 (836.600MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	GSM 850		836.600,	8.89	0.914	43.6
Head Simulating Liquid	10.00			190			

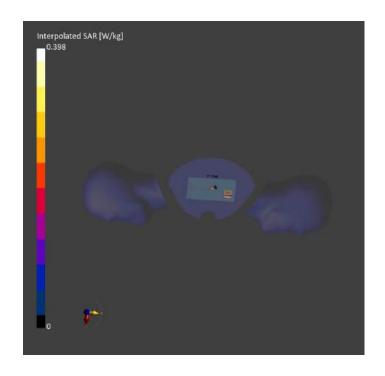
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-14	2025-03-14
psSAR1g [W/kg]	0.399	0.398
psSAR10g [W/kg]	0.267	0.255
Power Drift [dB]	-0.05	-0.11
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.6
Dist 3dB Peak [mm]		19.6



Measurement Report for Device, CHEEK, PCS 1900, Channel 512 (1850.200MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	CHEEK,	PCS 1900		1850.200,	7.33	1.42	41.7
Head Simulating Liquid	0.00			512			

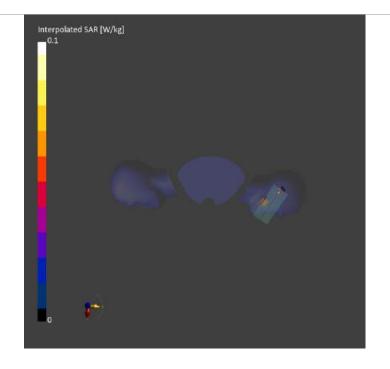
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	Υ
Surface Detection	VMS + 6p	All points
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-21	2025-03-21
psSAR1g [W/kg]	0.054	0.056
psSAR10g [W/kg]	0.031	0.035
Power Drift [dB]	-0.11	0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		89.5
Dist 3dB Peak [mm]		11.0



Measurement Report for Device, BACK, PCS 1900, Channel 512 (1850.200MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	PCS 1900		1850.200,	7.33	1.42	41.7
Head Simulating Liquid	10.00			512			

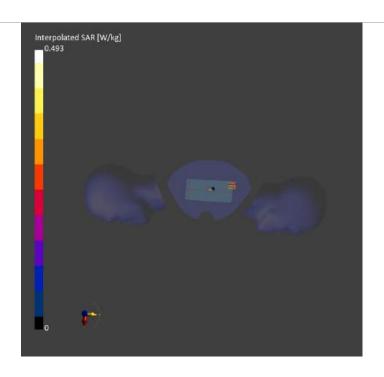
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) -	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18
22/13			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-21	2025-03-21
psSAR1g [W/kg]	0.430	0.495
psSAR10g [W/kg]	0.256	0.273
Power Drift [dB]	0.01	0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.7
Dist 3dB Peak [mm]		10.8



Measurement Report for Device, CHEEK, Band 2, Channel 9262 (1852.400MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	CHEEK,	Band 2		1852.400,	7.33	1.42	41.7
Head Simulating Liquid	0.00			9262			

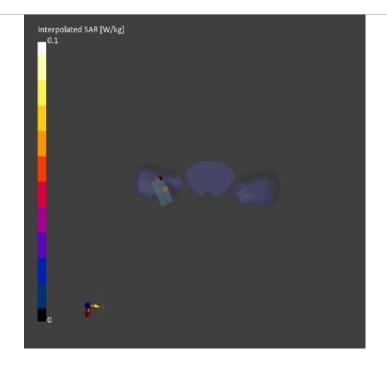
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	Υ
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-21	2025-03-21
psSAR1g [W/kg]	0.028	0.029
psSAR10g [W/kg]	0.016	0.018
Power Drift [dB]	-0.18	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		96.3
Dist 3dB Peak [mm]		11.4



Measurement Report for Device, BACK, Band 2, Channel 9262 (1852.400MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band 2		1852.400,	7.33	1.42	41.7
Head Simulating Liquid	10.00			9262			

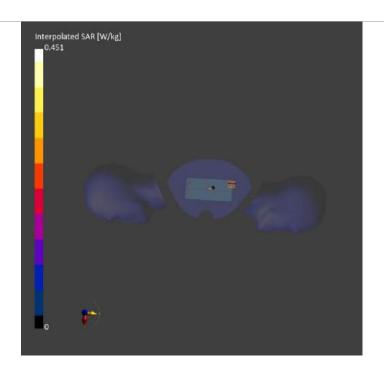
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-21	2025-03-21
psSAR1g [W/kg]	0.223	0.252
psSAR10g [W/kg]	0.132	0.138
Power Drift [dB]	-0.01	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.4
Dist 3dB Peak [mm]		10.8



Measurement Report for Device, CHEEK, Band 4, Channel 1312 (1712.400MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	CHEEK,	Band 4		1712.400,	7.6	1.33	42.0
Head Simulating Liquid	0.00			1312			

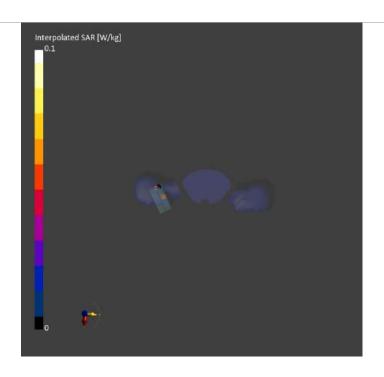
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	Υ
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-18	2025-03-18
psSAR1g [W/kg]	0.043	0.045
psSAR10g [W/kg]	0.025	0.029
Power Drift [dB]	0.03	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		93.5
Dist 3dB Peak [mm]		10.8



Measurement Report for Device, BACK, Band 4, Channel 1312 (1712.400MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band 4		1712.400,	7.6	1.33	42.0
Head Simulating Liquid	10.00			1312			

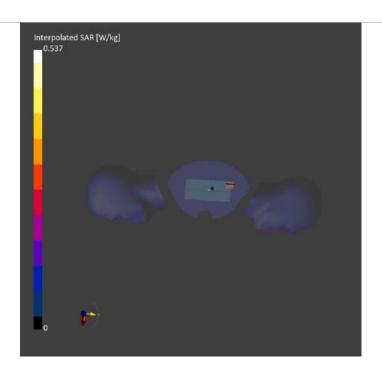
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-18	2025-03-18
psSAR1g [W/kg]	0.265	0.303
psSAR10g [W/kg]	0.161	0.169
Power Drift [dB]	-0.01	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.3
Dist 3dB Peak [mm]		10.8



Measurement Report for Device, CHEEK, Band 5, Channel 4233 (846.600MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	CHEEK,	Band 5		846.600,	8.89	0.914	43.6
Head Simulating Liquid	0.00			4233			

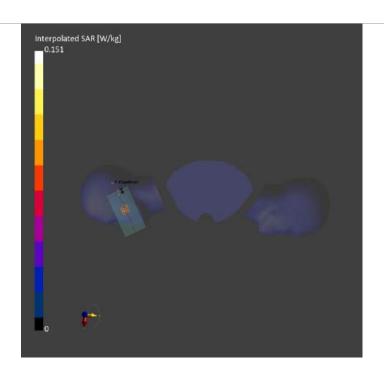
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-14	2025-03-14
psSAR1g [W/kg]	0.116	0.127
psSAR10g [W/kg]	0.081	0.102
Power Drift [dB]	0.02	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		95.7
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, BACK, Band 5, Channel 4233 (846.600MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type	
Device,	158.2 x 77.9 x 8.0		Phone	

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band 5		846.600,	8.89	0.914	43.6
Head Simulating Liquid	10.00			4233			

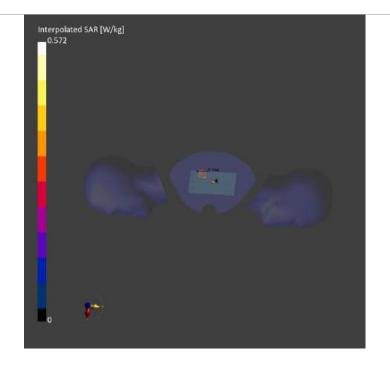
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-14	2025-03-14
psSAR1g [W/kg]	0.315	0.330
psSAR10g [W/kg]	0.209	0.210
Power Drift [dB]	-0.00	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.3
Dist 3dB Peak [mm]		17.9



Measurement Report for Device, CHEEK, Band 2, , Channel 18900 (1880.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	CHEEK,	Band 2		1880.000,	7.33	1.42	41.7
Head Simulating Liquid	0.00			18900			

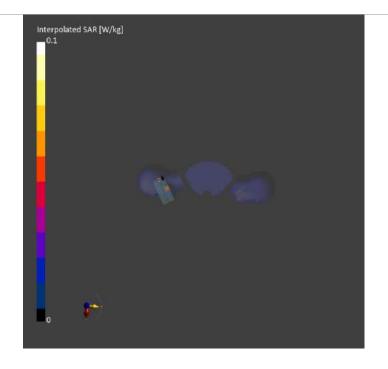
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	Υ
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-21	2025-03-21
psSAR1g [W/kg]	0.031	0.031
psSAR10g [W/kg]	0.017	0.019
Power Drift [dB]	-0.07	0.08
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		96.5
Dist 3dB Peak [mm]		11.4



Measurement Report for Device, BACK, Band 2, Channel 18700 (1860.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band 2		1860.000,	7.33	1.42	41.7
Head Simulating Liquid	10.00			18700			

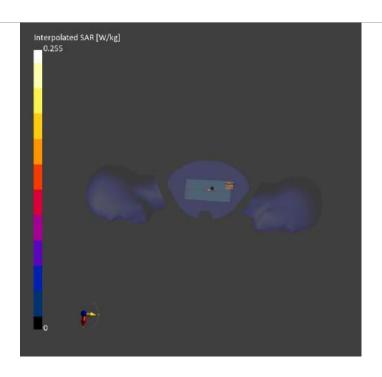
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-21	2025-03-21
psSAR1g [W/kg]	0.232	0.255
psSAR10g [W/kg]	0.136	0.141
Power Drift [dB]	-0.00	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.5
Dist 3dB Peak [mm]		10.8



Measurement Report for Device, CHEEK, Band 4, Channel 20325 (1747.500MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	CHEEK,	Band 4		1747.500,	7.6	1.33	42.0
Head Simulating Liquid	0.00			20325			

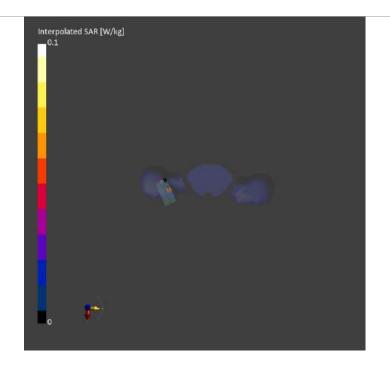
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	Υ
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-18	2025-03-18
psSAR1g [W/kg]	0.032	0.032
psSAR10g [W/kg]	0.019	0.021
Power Drift [dB]	-0.08	0.09
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		94.8
Dist 3dB Peak [mm]		13.5



Measurement Report for Device, BACK, Band 4, Channel 20325 (1747.500MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band 4		1747.500,	7.6	1.33	42.0
Head Simulating Liquid	10.00			20325			

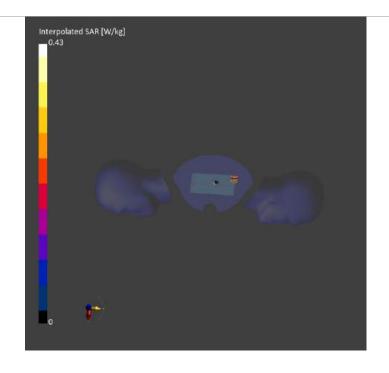
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-18	2025-03-18
psSAR1g [W/kg]	0.219	0.243
psSAR10g [W/kg]	0.131	0.135
Power Drift [dB]	-0.01	-0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		83.7
Dist 3dB Peak [mm]		10.8



Measurement Report for Device, CHEEK, Band 5, Channel 20425 (826.500MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	CHEEK,	Band 5		826.500,	8.89	0.914	43.6
Head Simulating Liquid	0.00			20425			

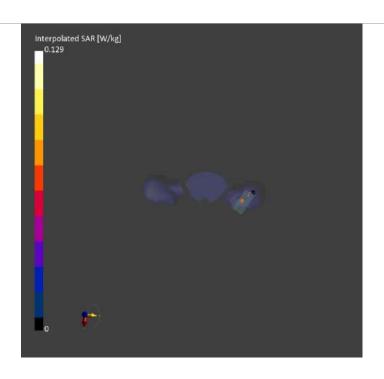
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

Area Scan	Zoom Scan
120.0 x 210.0	30.0 x 30.0 x 30.0
15.0 x 15.0	6.0 x 6.0 x 1.5
3.0	1.4
N/A	Yes
N/A	1.5
Υ	Υ
VMS + 6p	VMS + 6p
Measured	Measured
	120.0 x 210.0 15.0 x 15.0 3.0 N/A N/A Y VMS + 6p

	Area Scan	Zoom Scan
Date	2025-03-14	2025-03-14
psSAR1g [W/kg]	0.100	0.103
psSAR10g [W/kg]	0.068	0.079
Power Drift [dB]	-0.05	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		94.6
Dist 3dB Peak [mm]		20.4



Measurement Report for Device, BACK, Band 5, UID 10175 CAH, Channel 20425 (826.500MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band 5		826.500,	8.89	0.914	43.6
Head Simulating Liquid	10.00			20425			

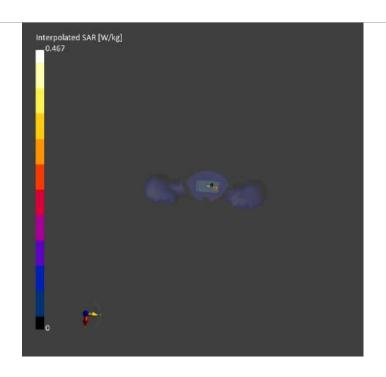
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-14	2025-03-14
psSAR1g [W/kg]	0.278	0.277
psSAR10g [W/kg]	0.182	0.176
Power Drift [dB]	0.00	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.8
Dist 3dB Peak [mm]		18.7



Measurement Report for Device, CHEEK, Band 7, Channel 21375 (2562.500MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	CHEEK,	Band 7		2562.500,	6.94	1.89	40.8
Head Simulating Liquid	0.00			21375			

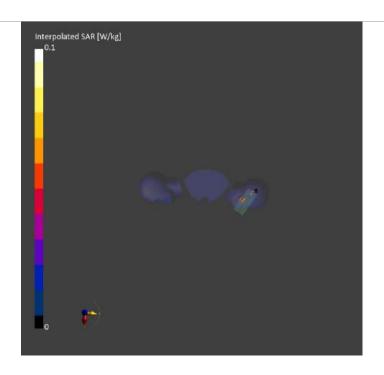
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

Area Scan	Zoom Scan
120.0 x 200.0	30.0 x 30.0 x 30.0
10.0 x 10.0	5.0 x 5.0 x 1.5
3.0	1.4
N/A	Yes
N/A	1.5
Υ	Υ
VMS + 6p	VMS + 6p
Measured	Measured
	120.0 x 200.0 10.0 x 10.0 3.0 N/A N/A Y VMS + 6p

	Area Scan	Zoom Scan
Date	2025-03-31	2025-03-31
psSAR1g [W/kg]	0.026	0.030
psSAR10g [W/kg]	0.014	0.015
Power Drift [dB]	-0.29	0.51
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		84.6
Dist 3dB Peak [mm]		8.1



Measurement Report for Device, BACK, Band 7, Channel 21375 (2562.500MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band 7		2562.500,	6.94	1.89	40.8
Head Simulating Liquid	10.00			21375			

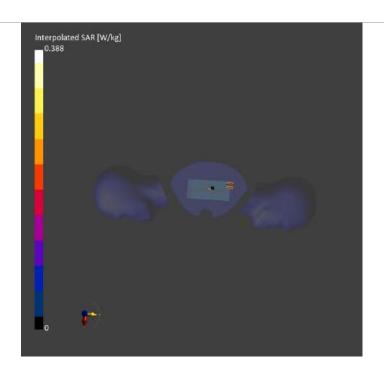
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	Υ
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-31	2025-03-31
psSAR1g [W/kg]	0.188	0.193
psSAR10g [W/kg]	0.094	0.094
Power Drift [dB]	0.03	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		79.7
Dist 3dB Peak [mm]		9.9



Measurement Report for Device, BACK, Band 12, Channel 23035 (701.500MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band 12		701.500,	9.16	0.871	44.0
Head Simulating	10.00			23035			
Liquid							

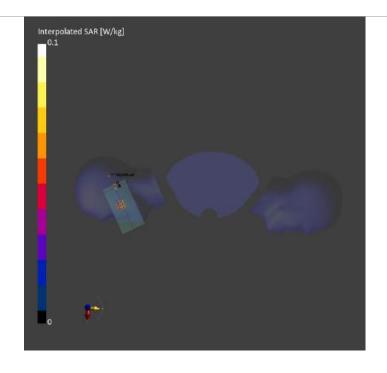
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-11	2025-03-11
psSAR1g [W/kg]	0.179	0.181
psSAR10g [W/kg]	0.118	0.112
Power Drift [dB]	0.02	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.3
Dist 3dB Peak [mm]		13.3



Measurement Report for Device, BACK, Band 12, Channel 23035 (701.500MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band 12		701.500,	9.16	0.871	44.0
Head Simulating Liquid	10.00			23035			

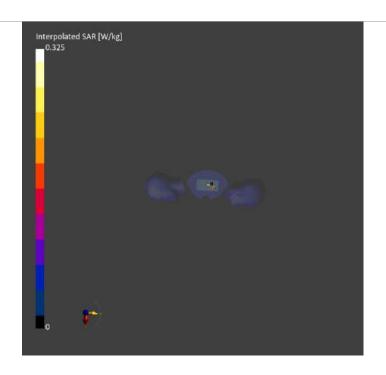
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-11	2025-03-11
psSAR1g [W/kg]	0.179	0.181
psSAR10g [W/kg]	0.118	0.112
Power Drift [dB]	0.02	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.3
Dist 3dB Peak [mm]		13.3



Measurement Report for Device, CHEEK, Band 17, Channel 23825 (713.500MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	CHEEK,	Band 17		713.500,	9.16	0.872	44.0
Head Simulating Liquid	0.00			23825			

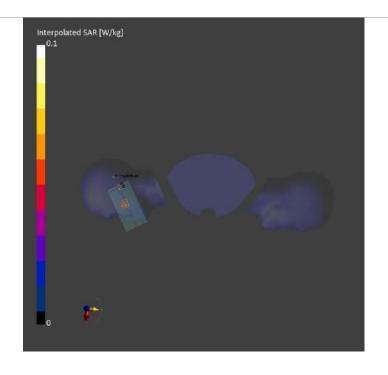
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	Υ
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-11	2025-03-11
psSAR1g [W/kg]	0.043	0.047
psSAR10g [W/kg]	0.030	0.038
Power Drift [dB]	0.04	0.00
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		95.5
Dist 3dB Peak [mm]		> 15.0



Measurement Report for Device, BACK, Band 17, Channel 23825 (713.500MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band 17		713.500,	9.16	0.872	44.0
Head Simulating Liquid	10.00			23825			

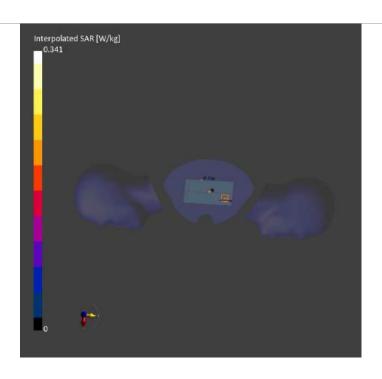
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-11	2025-03-11
psSAR1g [W/kg]	0.193	0.191
psSAR10g [W/kg]	0.127	0.118
Power Drift [dB]	-0.01	-0.02
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.0
Dist 3dB Peak [mm]		12.6



Measurement Report for Device, CHEEK, Band 38, Channel 38175 (2612.500MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	CHEEK,	Band 38		2612.500,	6.94	1.94	40.8
Head Simulating Liquid	0.00			38175			

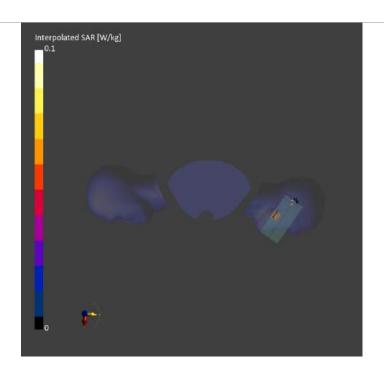
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	Υ
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-11	2025-03-11
psSAR1g [W/kg]	0.052	0.056
psSAR10g [W/kg]	0.025	0.028
Power Drift [dB]	0.07	0.09
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		87.7
Dist 3dB Peak [mm]		7.1



Measurement Report for Device, BACK, Band 38, Channel 38175 (2612.500MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band 38	LTE-TDD,	2612.500,	6.94	1.94	40.8
Head Simulating Liquid	10.00		10172-CAH	3175			

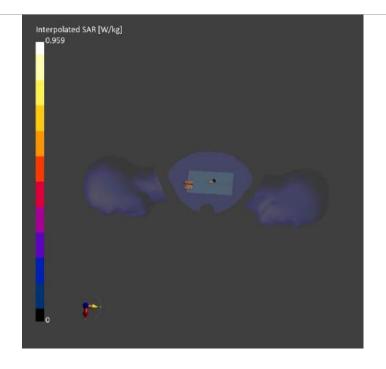
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-31	2025-03-31
psSAR1g [W/kg]	0.417	0.436
psSAR10g [W/kg]	0.195	0.196
Power Drift [dB]	-0.00	-0.09
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		77.7
Dist 3dB Peak [mm]		8.1



Measurement Report for Device, CHEEK, Band 41, Channel 40620 (2593.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	CHEEK,	Band 41		2593.000,	6.94	1.90	40.8
Head Simulating Liquid	0.00			40620			

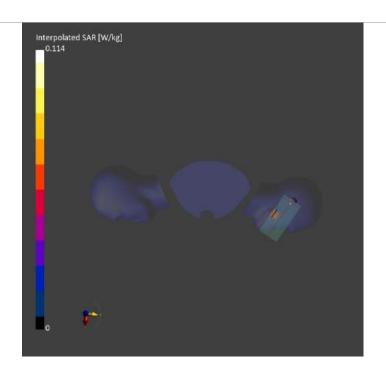
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	Υ
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-27	2025-03-27
psSAR1g [W/kg]	0.059	0.064
psSAR10g [W/kg]	0.030	0.032
Power Drift [dB]	0.02	0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		87.5
Dist 3dB Peak [mm]		8.1



Measurement Report for Device, BACK, Band 41, Channel 40620 (2593.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band 41		2593.000,	6.94	1.90	40.8
Head Simulating	10.00			40620			
Liquid							

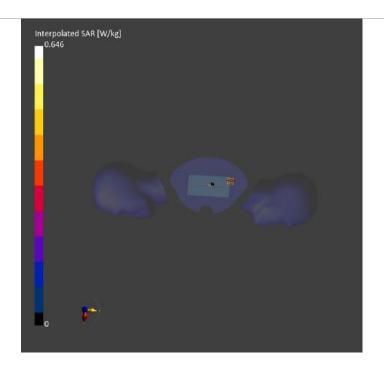
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-27	2025-03-27
psSAR1g [W/kg]	0.310	0.319
psSAR10g [W/kg]	0.153	0.152
Power Drift [dB]	-0.06	-0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.6
Dist 3dB Peak [mm]		9.9



Measurement Report for Device, TILT, Band 42, Channel 42190 (3460.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	TILT,	Band 42		3460.000,	6.22	2.72	39.2
Head Simulating	0.00			42190			
Liquid							

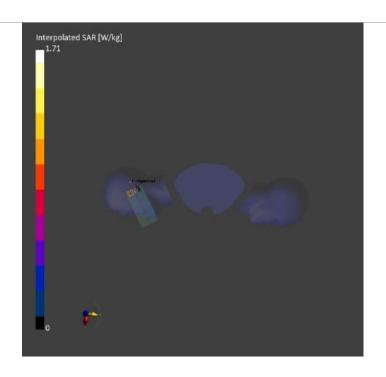
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-04-09	2025-04-09
psSAR1g [W/kg]	0.530	0.562
psSAR10g [W/kg]	0.176	0.181
Power Drift [dB]	-0.27	-0.17
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		71.7
Dist 3dB Peak [mm]		5.9



Measurement Report for Device, BACK, Band 42, Channel 42190 (3460.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band 42		3460.000,	6.22	2.72	39.2
Head Simulating Liquid	10.00			42190			

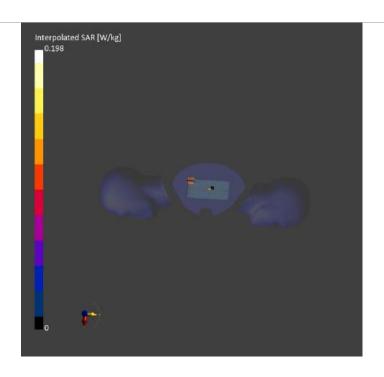
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	Υ
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-04-09	2025-04-09
psSAR1g [W/kg]	0.085	0.084
psSAR10g [W/kg]	0.039	0.036
Power Drift [dB]	-0.22	-0.36
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		74.6
Dist 3dB Peak [mm]		10.5



Measurement Report for Device, CHEEK, WLAN 2.4GHz, Channel 11 (2462.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	CHEEK,	WLAN		2462.000,	6.88	1.81	41.0
Head Simulating Liquid	0.00	2.4GHz		11			

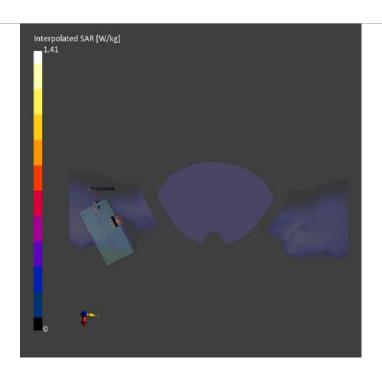
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) -	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18
22/12			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-23	2025-03-23
psSAR1g [W/kg]	0.594	0.617
psSAR10g [W/kg]	0.266	0.266
Power Drift [dB]	-0.04	0.35
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		77.7
Dist 3dB Peak [mm]		7.1



Measurement Report for Device, BACK, WLAN 2.4GHz, Channel 11 (2462.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	WLAN		2462.000,	6.88	1.82	41.0
Head Simulating Liquid	10.00	2.4GHz		11			

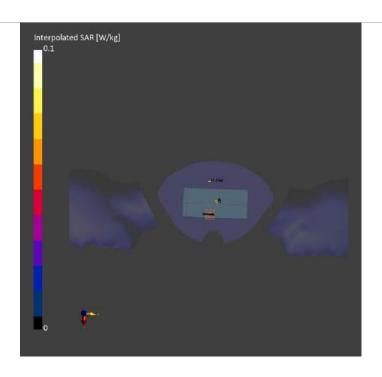
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	Υ
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-23	2025-03-23
psSAR1g [W/kg]	0.036	0.039
psSAR10g [W/kg]	0.018	0.019
Power Drift [dB]	-0.09	-0.28
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		76.3
Dist 3dB Peak [mm]		9.0



Measurement Report for Device, TILT, WLAN 5GHz, Channel 48 (5240.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	TILT,	WLAN		5240.000,	5.34	4.51	36.4
Head Simulating Liquid	0.00	5GHz		48			

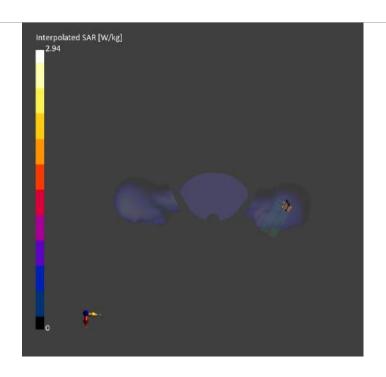
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-21	2025-03-21
psSAR1g [W/kg]	0.587	0.686
psSAR10g [W/kg]	0.141	0.160
Power Drift [dB]	0.60	0.96
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		63.0
Dist 3dB Peak [mm]		5.2



Measurement Report for Device, BACK, WLAN 5GHz, Channel 48 (5240.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	WLAN		5240.000,	5.34	4.51	36.4
Head Simulating Liquid	10.00	5GHz		48			

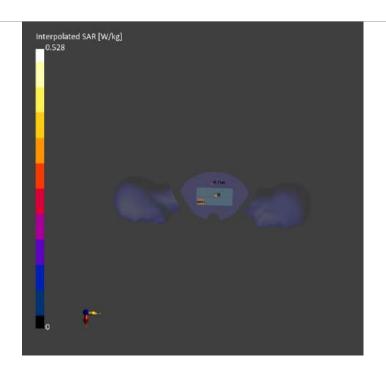
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Υ	Υ
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-04-21	2025-04-21
psSAR1g [W/kg]	0.147	0.142
psSAR10g [W/kg]	0.057	0.053
Power Drift [dB]	-0.13	-0.49
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		63.2
Dist 3dB Peak [mm]		9.4



Measurement Report for Device, TILT, WLAN 5GHz, Channel 64 (5320.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	TILT,	WLAN		5320.000,	5.28	4.68	36.1
Head Simulating	0.00	5GHz		64			

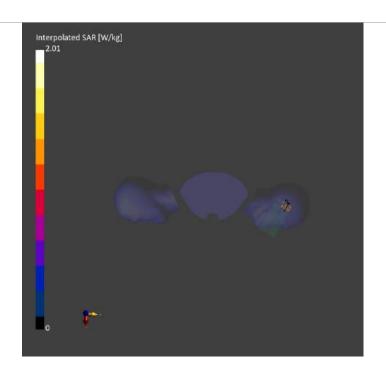
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) -	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18
22/13			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Υ	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-04-25	2025-04-25
psSAR1g [W/kg]	0.347	0.408
psSAR10g [W/kg]	0.081	0.094
Power Drift [dB]	0.80	-0.06
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		58.9
Dist 3dB Peak [mm]		4.1



Measurement Report for Device, BACK, WLAN 5GHz, Channel 64 (5320.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	WLAN		5320.000,	5.28	4.68	36.1
Head Simulating Liquid	10.00	5GHz		64			

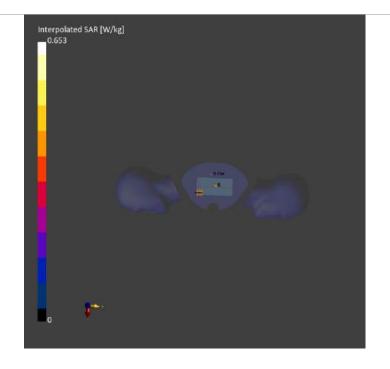
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Υ	Υ
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-04-25	2025-04-25
psSAR1g [W/kg]	0.167	0.185
psSAR10g [W/kg]	0.067	0.069
Power Drift [dB]	0.29	0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		61.2
Dist 3dB Peak [mm]		8.9



Measurement Report for Device, TILT, WLAN 5GHz, Channel 100 (5500.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	TILT,	WLAN		5500.000,	4.84	5.17	35.4
Head Simulating Liquid	0.00	5GHz		100			

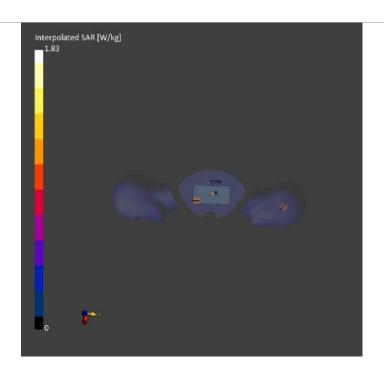
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date	
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18	

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Υ	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-04-25	2025-04-25
psSAR1g [W/kg]	0.357	0.398
psSAR10g [W/kg]	0.111	0.112
Power Drift [dB]	-0.23	0.37
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		64.5
Dist 3dB Peak [mm]		5.1



Measurement Report for Device, BACK, WLAN 5GHz, Channel 100 (5500.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	WLAN		5500.000,	4.84	5.17	35.4
Head Simulating Liquid	10.00	5GHz		100			

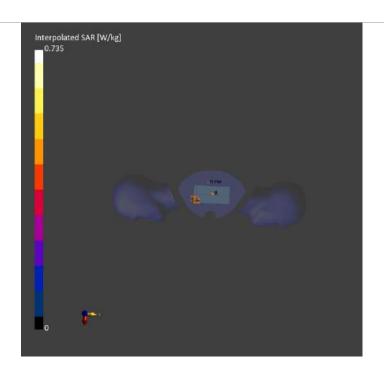
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Υ	Υ
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-04-25	2025-04-25
psSAR1g [W/kg]	0.149	0.169
psSAR10g [W/kg]	0.055	0.053
Power Drift [dB]	0.95	0.16
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		58.2
Dist 3dB Peak [mm]		7.9



Measurement Report for Device, TILT, WLAN 5GHz, Channel 100 (5795.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type	
Device,	158.2 x 77.9 x 8.0		Phone	

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	TILT,	WLAN		5795.000,	4.87	5.11	35.4
Head Simulating Liquid	0.00	5GHz		100			

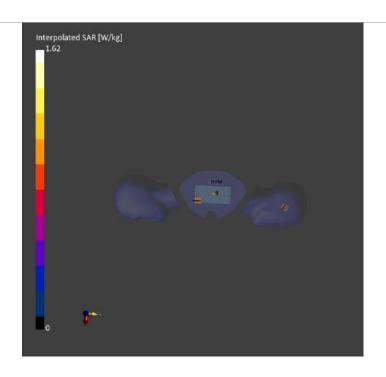
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Υ	Υ
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-04-28	2025-04-28
psSAR1g [W/kg]	0.313	0.356
psSAR10g [W/kg]	0.096	0.101
Power Drift [dB]	0.01	0.03
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		58.4
Dist 3dB Peak [mm]		5.1



Measurement Report for Device, BACK, WLAN 5GHz, Channel 159 (5795.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	158.2 x 77.9 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	WLAN		5795.000,	4.87	5.11	35.4
Head Simulating Liquid	10.00	5GHz		159			

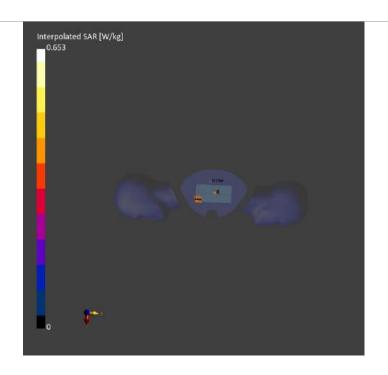
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 2243	HBBL-600-10000 Charge:xxxx,	EX3DV4 - SN7895, 2024-10-28	DAE4ip Sn1872, 2024-10-18

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	22.0 x 22.0 x 22.0
Grid Steps [mm]	10.0 x 10.0	4.0 x 4.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.4
MAIA	Υ	Υ
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-04-28	2025-04-28
psSAR1g [W/kg]	0.101	0.104
psSAR10g [W/kg]	0.036	0.034
Power Drift [dB]	0.05	0.20
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		61.0
Dist 3dB Peak [mm]		8.7



Measurement Report for Device, CHEEK, Band n5, Channel 165800 (829.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	CHEEK,	Band n5		829.000,	10.45	0.912	41.5
HBBL 5-	0.00			165800			
10000MHz							

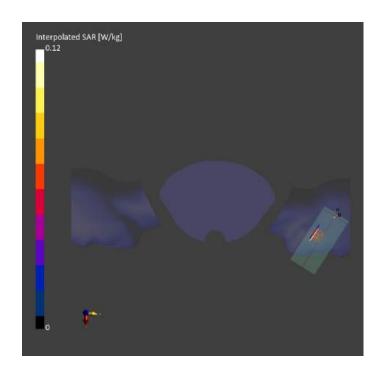
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 1901	HBBL 5-10000MHz ,	EX3DV4 - SN7391, 2024-11-29	DAE4 Sn1495, 2024-07-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-14	2025-03-14
psSAR1g [W/kg]	0.115	0.120
psSAR10g [W/kg]	0.078	0.087
Power Drift [dB]	-0.15	-0.05
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		91.2
Dist 3dB Peak [mm]		20.7



Measurement Report for Device, BACK, Band n5, Channel 165800 (829.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band n5		829.000,	10.45	0.912	41.5
HBBL 5-	10.00			165800			
10000MHz							

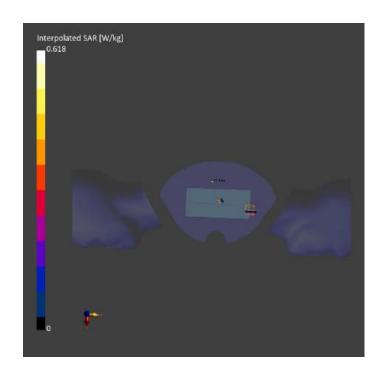
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) -	HBBL 5-10000MHz ,	EX3DV4 - SN7391, 2024-11-29	DAE4 Sn1495, 2024-07-24
1901			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-14	2025-03-14
psSAR1g [W/kg]	0.160	0.168
psSAR10g [W/kg]	0.108	0.107
Power Drift [dB]	-0.05	-0.12
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No	No correction
	correction	
M2/M1 [%]		83.2
Dist 3dB Peak [mr	n]	18.0



Measurement Report for Device, CHEEK, Band n7, Channel 500500 (2505.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type	
Device.	165.0 x 75.0 x 8.0		Phone	

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	CHEEK,	Band n7		2505.000,	7.9	1.90	39.1
HBBL 5-	0.00			500500			
10000MHz							

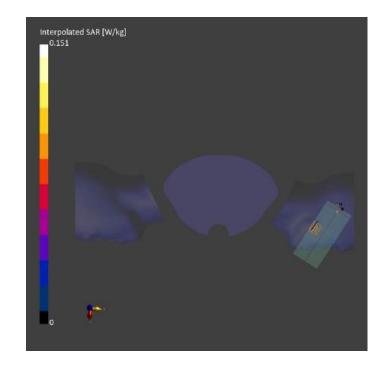
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 1901	HBBL 5-10000MHz ,	EX3DV4 - SN7391, 2024-11-29	DAE4 Sn1495, 2024-07-24

Scan Setup

Area Scan	Zoom Scan
120.0 x 200.0	30.0 x 30.0 x 30.0
10.0 x 10.0	5.0 x 5.0 x 1.5
3.0	1.4
N/A	Yes
N/A	1.5
Υ	Υ
VMS + 6p	VMS + 6p
Measured	Measured
	120.0 x 200.0 10.0 x 10.0 3.0 N/A N/A Y VMS + 6p

	Area Scan	Zoom Scan
Date	2025-03-27	2025-03-27
psSAR1g [W/kg]	0.144	0.151
psSAR10g [W/kg]	0.075	0.078
Power Drift [dB]	-0.03	0.20
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.6
Dist 3dB Peak [mm]		9.9



Measurement Report for Device, BACK, Band n7, Channel 500500 (2505.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band n7		2505.000,	7.9	1.90	39.1
HBBL 5-	10.00			500500			
10000MHz							

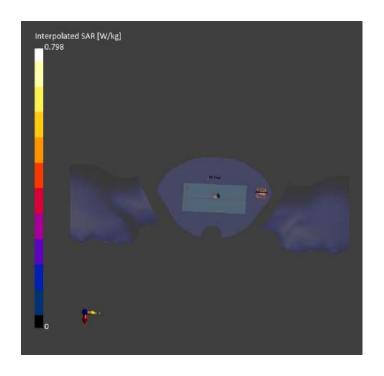
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) -	HBBL 5-10000MHz ,	EX3DV4 - SN7391, 2024-11-29	DAE4 Sn1495, 2024-07-24
1901			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-27	2025-03-27
psSAR1g [W/kg]	0.755	0.798
psSAR10g [W/kg]	0.355	0.367
Power Drift [dB]	-0.03	-0.10
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		79.7
Dist 3dB Peak [mm]		9.5



Measurement Report for Device, CHEEK, Band n12, Channel 140800 (704.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	CHEEK,	Band n12		704.000,	10.45	0.891	42.2
HBBL 5-	0.00			140800			
10000MHz							

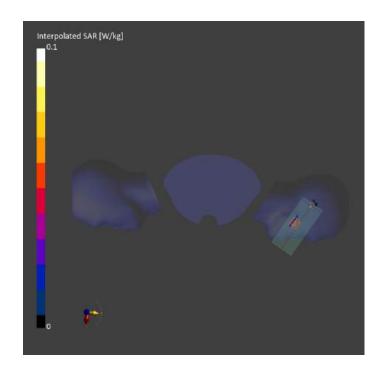
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 1901	HBBL 5-10000MHz ,	EX3DV4 - SN7391, 2024-11-29	DAE4 Sn1495, 2024-07-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	Υ
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-11	2025-03-11
psSAR1g [W/kg]	0.059	0.059
psSAR10g [W/kg]	0.040	0.042
Power Drift [dB]	-0.13	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		90.5
Dist 3dB Peak [mm]		16.8



Measurement Report for Device, BACK, Band n12, Channel 140800 (704.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band n12		704.000,	10.45	0.891	42.2
HBBL 5-	10.00			140800			
10000MHz							

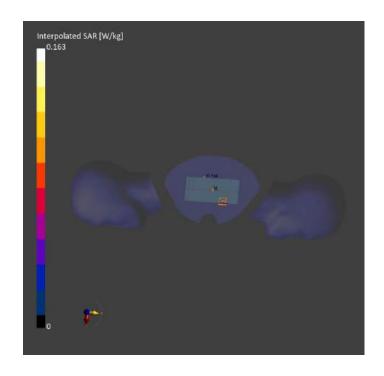
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 1901	HBBL 5-10000MHz ,	EX3DV4 - SN7391, 2024-11-29	DAE4 Sn1495, 2024-07-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-11	2025-03-11
psSAR1g [W/kg]	0.163	0.163
psSAR10g [W/kg]	0.109	0.101
Power Drift [dB]	-0.06	-0.12
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		80.4
Dist 3dB Peak [mm]		14.4



Measurement Report for Device, CHEEK, Band n38, Channel 519000 (2595.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	CHEEK,	Band n38		2595.000,	7.7	1.96	39.0
HBBL 5-	0.00			519000			
10000MHz							

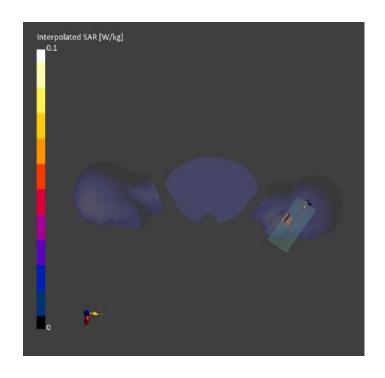
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
	HBBL 5-10000MHz ,	EX3DV4 - SN7391, 2024-11-29	DAE4 Sn1495, 2024-07-24
1901			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	Υ
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-31	2025-03-31
psSAR1g [W/kg]	0.026	0.027
psSAR10g [W/kg]	0.012	0.013
Power Drift [dB]	-0.31	0.51
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.7
Dist 3dB Peak [mm]		8.1



Measurement Report for Device, BACK, Band n38, Channel 519000 (2595.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band n38		2595.000,	7.7	1.96	39.0
HBBL 5-	10.00			519000			
10000MHz							

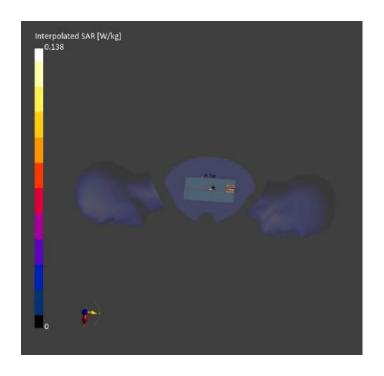
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) -	HBBL 5-10000MHz ,	EX3DV4 - SN7391, 2024-11-29	DAE4 Sn1495, 2024-07-24
1901			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	Υ
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-31	2025-03-31
psSAR1g [W/kg]	0.135	0.138
psSAR10g [W/kg]	0.065	0.064
Power Drift [dB]	-0.09	-0.04
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		78.4
Dist 3dB Peak [mm]		9.9



Measurement Report for Device, CHEEK, Band n41, Channel 501204 (2506.00MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	CHEEK,	Band n41		2506.000,	7.7	1.96	39.0
HBBL 5-	0.00			501204			
10000MHz							

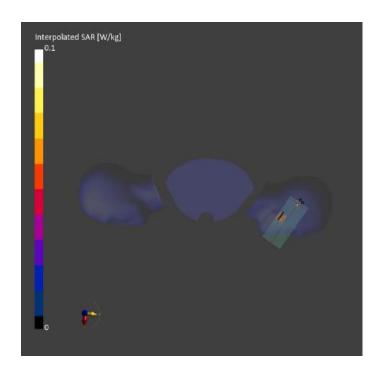
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 1901	HBBL 5-10000MHz ,	EX3DV4 - SN7391, 2024-11-29	DAE4 Sn1495, 2024-07-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	Υ
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-27	2025-03-27
psSAR1g [W/kg]	0.028	0.029
psSAR10g [W/kg]	0.014	0.014
Power Drift [dB]	0.28	0.20
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		82.1
Dist 3dB Peak [mm]		10.2



Measurement Report for Device, BACK, Band n41, Channel 501204 (2506.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band n41		2506.000,	7.7	1.96	39.0
HBBL 5-	10.00			501204			
10000MHz							

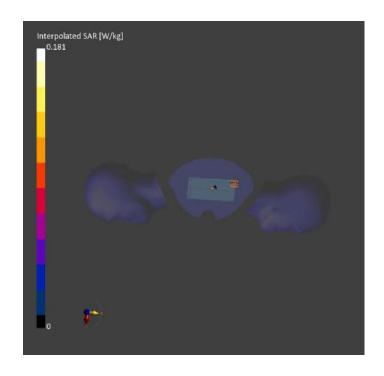
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 1901	HBBL 5-10000MHz ,	EX3DV4 - SN7391, 2024-11-29	DAE4 Sn1495, 2024-07-24

Scan Setup

Area Scan	Zoom Scan
120.0 x 200.0	30.0 x 30.0 x 30.0
10.0 x 10.0	5.0 x 5.0 x 1.5
3.0	1.4
N/A	Yes
N/A	1.5
Υ	Υ
VMS + 6p	VMS + 6p
Measured	Measured
	120.0 x 200.0 10.0 x 10.0 3.0 N/A N/A Y VMS + 6p

	Area Scan	Zoom Scan
Date	2025-03-27	2025-03-27
psSAR1g [W/kg]	0.176	0.181
psSAR10g [W/kg]	0.082	0.082
Power Drift [dB]	-0.03	-0.01
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		78.7
Dist 3dB Peak [mm]		9.5



Measurement Report for Device, CHEEK, Band n66, Channel 349000 (1745.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	CHEEK,	Band n66		1745.000,	8.72	1.37	40.1
HBBL 5-	0.00			349000			
10000MHz							

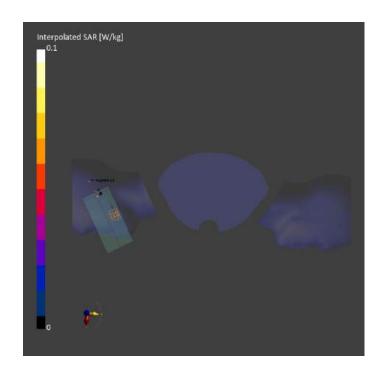
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 1901	HBBL 5-10000MHz ,	EX3DV4 - SN7391, 2024-11-29	DAE4 Sn1495, 2024-07-24

Scan Setup

Area Scan	Zoom Scan
120.0 x 210.0	30.0 x 30.0 x 30.0
15.0 x 15.0	6.0 x 6.0 x 1.5
3.0	1.4
N/A	Yes
N/A	1.5
Υ	Υ
All points	VMS + 6p
Measured	Measured
	120.0 x 210.0 15.0 x 15.0 3.0 N/A N/A Y All points

	Area Scan	Zoom Scan
Date	2025-03-18	2025-03-18
psSAR1g [W/kg]	0.080	0.085
psSAR10g [W/kg]	0.047	0.051
Power Drift [dB]	0.41	0.19
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		87.2
Dist 3dB Peak [mm]		13.2



Measurement Report for Device, BACK, Band n66, Channel 349000 (1745.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band n66		1745.000,	8.72	1.37	40.1
HBBL 5-	10.00			349000			
10000MHz							

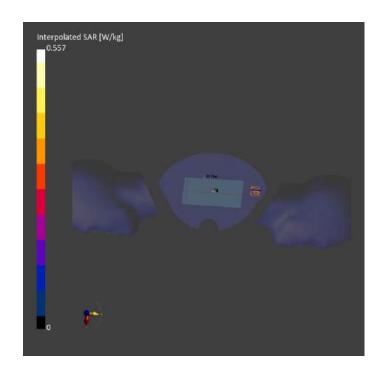
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 1901	HBBL 5-10000MHz ,	EX3DV4 - SN7391, 2024-11-29	DAE4 Sn1495, 2024-07-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	N/A	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-18	2025-03-18
psSAR1g [W/kg]	0.557	0.569
psSAR10g [W/kg]	0.320	0.304
Power Drift [dB]	-0.35	-0.11
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		81.4
Dist 3dB Peak [mm]		9.2



Measurement Report for Device, CHEEK, Band n71, Channel 136100 (680.500MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
LeftHead,	CHEEK,	Band n71		680.500,	10.45	0.889	42.3
HBBL 5-	0.00			136100			
10000MHz							

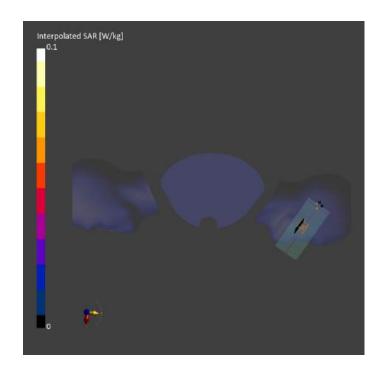
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 1901	HBBL 5-10000MHz ,	EX3DV4 - SN7391, 2024-11-29	DAE4 Sn1495, 2024-07-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	Υ
Surface Detection	VMS + 6p	All points
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-11	2025-03-11
psSAR1g [W/kg]	0.011	0.010
psSAR10g [W/kg]	0.007	0.007
Power Drift [dB]	-0.71	-0.19
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		91.2
Dist 3dB Peak [mm]		13.4



Measurement Report for Device, BACK, Band n71, Channel 136100 (680.500MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band n71		680.500,	10.45	0.889	42.3
HBBL 5-	10.00			136100			
10000MHz							

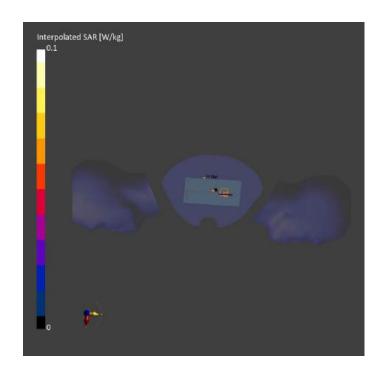
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) -	HBBL 5-10000MHz ,	EX3DV4 - SN7391, 2024-11-29	DAE4 Sn1495, 2024-07-24
1901			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 210.0	30.0 x 30.0 x 30.0
Grid Steps [mm]	15.0 x 15.0	6.0 x 6.0 x 1.5
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-03-11	2025-03-11
psSAR1g [W/kg]	0.059	0.064
psSAR10g [W/kg]	0.040	0.038
Power Drift [dB]	0.10	-0.14
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		78.4
Dist 3dB Peak [mm]		12.4



Measurement Report for Device, TILT, Band n77, Channel 633334 (3500.010MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	TILT,	Band n77		3500.010,	7.0	2.92	37.9
HBBL 5-	0.00			633334			
10000MHz							

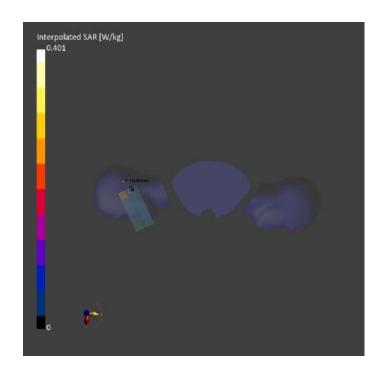
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) -	HBBL 5-10000MHz ,	EX3DV4 - SN7391, 2024-11-29	DAE4 Sn1495, 2024-07-24
1901			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-04-09	2025-04-09
psSAR1g [W/kg]	0.365	0.401
psSAR10g [W/kg]	0.121	0.124
Power Drift [dB]	-0.05	-0.18
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		69.1
Dist 3dB Peak [mm]		4.8



Measurement Report for Device, BACK, Band n77, Channel 633334 (3500.010MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band n77		3500.010,	7.0	2.92	37.9
HBBL 5-	10.00			633334			
10000MHz							

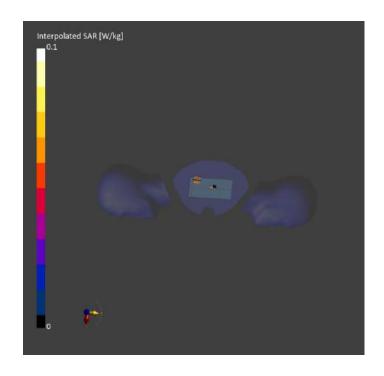
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) -	HBBL 5-10000MHz ,	EX3DV4 - SN7391, 2024-11-29	DAE4 Sn1495, 2024-07-24
1901			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	Υ
Surface Detection	All points	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-04-09	2025-04-09
psSAR1g [W/kg]	0.066	0.068
psSAR10g [W/kg]	0.029	0.028
Power Drift [dB]	-0.23	-0.14
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		75.4
Dist 3dB Peak [mm]		10.3



Measurement Report for Device, TILT, Band n77, Channel 637000 (3560.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	TILT,	Band n77		3560.000,	6.8	3.04	37.8
HBBL 5-	0.00			637000			
10000MHz							

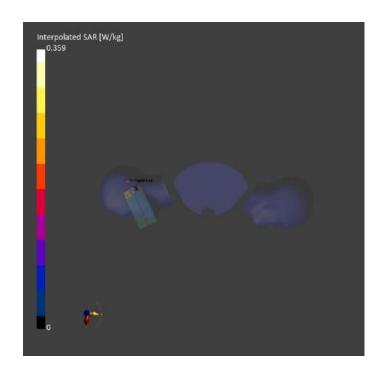
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 1901	HBBL 5-10000MHz ,	EX3DV4 - SN7391, 2024-11-29	DAE4 Sn1495, 2024-07-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-04-09	2025-04-09
psSAR1g [W/kg]	0.322	0.359
psSAR10g [W/kg]	0.105	0.108
Power Drift [dB]	0.01	-0.17
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		71.2
Dist 3dB Peak [mm]		6.1



Measurement Report for Device, BACK, Band n77, Channel 637000 (3560.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band n77		3560.000,	6.8	3.04	37.8
HBBL 5-	10.00			637000			
10000MHz							

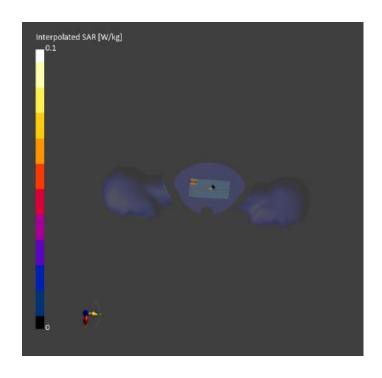
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 1901	HBBL 5-10000MHz ,	EX3DV4 - SN7391, 2024-11-29	DAE4 Sn1495, 2024-07-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	Υ
Surface Detection	All points	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-04-09	2025-04-09
psSAR1g [W/kg]	0.061	0.064
psSAR10g [W/kg]	0.026	0.026
Power Drift [dB]	0.10	-0.15
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		75.2
Dist 3dB Peak [mm]		9.9



Measurement Report for Device, TILT, Band n77, Channel 656000 (3890.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	TILT,	Band n77		3890.000,	6.7	3.27	37.5
HBBL 5-	0.00			656000			
10000MHz							

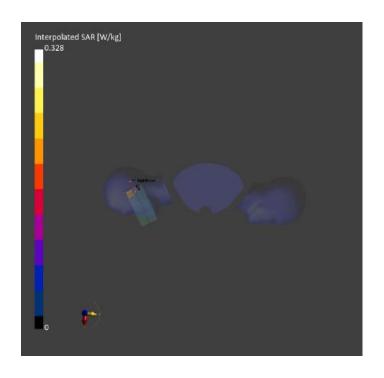
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 1901	HBBL 5-10000MHz ,	EX3DV4 - SN7391, 2024-11-29	DAE4 Sn1495, 2024-07-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-04-17	2025-04-17
psSAR1g [W/kg]	0.281	0.328
psSAR10g [W/kg]	0.091	0.097
Power Drift [dB]	-0.03	-0.11
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		68.5
Dist 3dB Peak [mm]		5.4



Measurement Report for Device, BACK, Band n77, Channel 656000 (3890.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band n77		3890.000,	6.7	3.27	37.5
HBBL 5-	10.00			656000			
10000MHz							

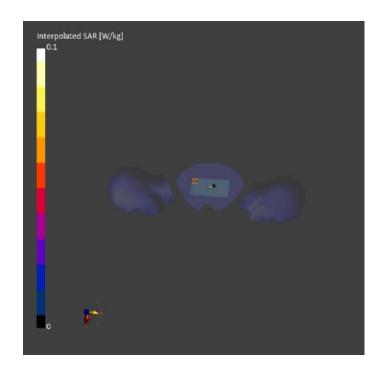
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) -	HBBL 5-10000MHz ,	EX3DV4 - SN7391, 2024-11-29	DAE4 Sn1495, 2024-07-24
1901			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	Υ
Surface Detection	All points	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-04-17	2025-04-17
psSAR1g [W/kg]	0.065	0.070
psSAR10g [W/kg]	0.027	0.028
Power Drift [dB]	-0.24	-0.19
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		72.1
Dist 3dB Peak [mm]		9.3



Measurement Report for Device, TILT, Band n78, Channel 633334 (3500.010MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	TILT,	Band n78		3500.010,	7.0	2.92	37.9
HBBL 5-	0.00			633334			
10000MHz							

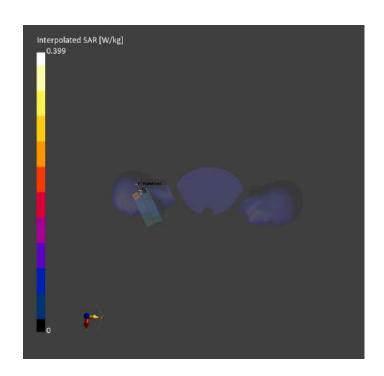
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 1901	HBBL 5-10000MHz ,	EX3DV4 - SN7391, 2024-11-29	DAE4 Sn1495, 2024-07-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-04-09	2025-04-09
psSAR1g [W/kg]	0.362	0.399
psSAR10g [W/kg]	0.121	0.125
Power Drift [dB]	-0.07	-0.10
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		68.6
Dist 3dB Peak [mm]		4.9



Measurement Report for Device, BACK, Band n78, Channel 633334 (3500.010MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band n78		3500.010,	7.0	2.92	37.9
HBBL 5-	10.00			633334			
10000MHz							

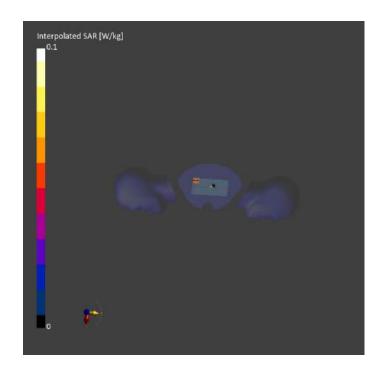
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) -	HBBL 5-10000MHz ,	EX3DV4 - SN7391, 2024-11-29	DAE4 Sn1495, 2024-07-24
1901			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	Υ
Surface Detection	All points	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-04-09	2025-04-09
psSAR1g [W/kg]	0.064	0.068
psSAR10g [W/kg]	0.028	0.028
Power Drift [dB]	-0.12	-0.19
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		75.8
Dist 3dB Peak [mm]		9.9



Measurement Report for Device, TILT, Band n78, Channel 638334 (3575.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	TILT,	Band n78		3575.000,	6.8	3.04	37.8
HBBL 5-	0.00			638334			
10000MHz							

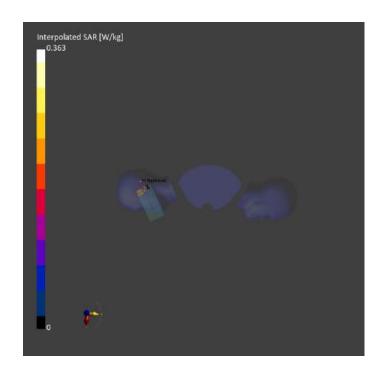
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 1901	HBBL 5-10000MHz ,	EX3DV4 - SN7391, 2024-11-29	DAE4 Sn1495, 2024-07-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-04-09	2025-04-09
psSAR1g [W/kg]	0.323	0.363
psSAR10g [W/kg]	0.106	0.111
Power Drift [dB]	-0.07	-0.16
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		71.1
Dist 3dB Peak [mm]		5.1



Measurement Report for Device, BACK, Band n78, Channel 638334 (3575.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type	
Device.	165.0 x 75.0 x 8.0		Phone	

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band n78		3575.000,	6.8	3.04	37.8
HBBL 5-	10.00			638334			
10000MHz							

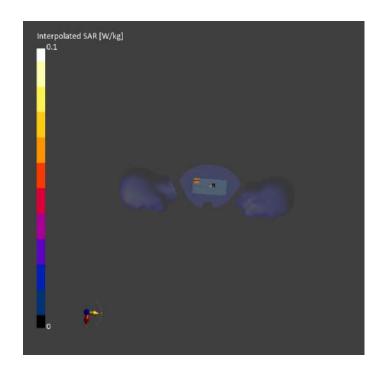
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 1901	HBBL 5-10000MHz ,	EX3DV4 - SN7391, 2024-11-29	DAE4 Sn1495, 2024-07-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	Υ
Surface Detection	All points	VMS + 6p
Scan Method	Measured	Measured
Sensor Surface [mm] Graded Grid Grading Ratio MAIA Surface Detection	3.0 N/A N/A Y All points	1 Y 1 VMS + 6

	Area Scan	Zoom Scan
Date	2025-04-09	2025-04-09
psSAR1g [W/kg]	0.052	0.054
psSAR10g [W/kg]	0.023	0.023
Power Drift [dB]	-0.03	-0.16
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		73.9
Dist 3dB Peak [mm]		10.3



Measurement Report for Device, TILT, Band n78, Channel 650000 (3750.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
RightHead,	TILT,	Band n78		3750.000,	6.8	3.17	37.6
HBBL 5-	0.00			650000			
10000MHz							

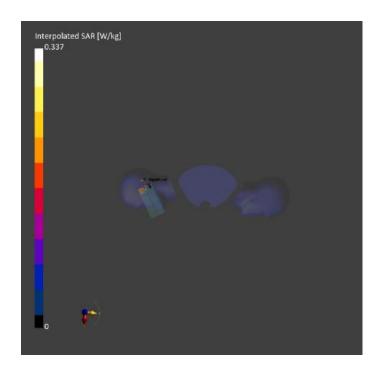
Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) - 1901	HBBL 5-10000MHz ,	EX3DV4 - SN7391, 2024-11-29	DAE4 Sn1495, 2024-07-24

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	N/A
Surface Detection	VMS + 6p	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-04-12	2025-04-12
psSAR1g [W/kg]	0.293	0.337
psSAR10g [W/kg]	0.095	0.101
Power Drift [dB]	-0.08	-0.15
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		69.3
Dist 3dB Peak [mm]		5.2



Measurement Report for Device, BACK, Band n78, Channel 650000 (3750.000MHz)

Device under Test Properties

Model, Manufacturer	Dimensions [mm]	IMEI	DUT Type
Device,	165.0 x 75.0 x 8.0		Phone

Exposure Conditions

Phantom Section, TSL	Position, Test Distance [mm]	Band	Group, UID	Frequency [MHz], Channel Number	Conversion Factor	TSL Conductivity [S/m]	TSL Permittivity
Flat,	BACK,	Band n78		3750.000,	6.8	3.17	37.6
HBBL 5-	10.00			650000			
10000MHz							

Hardware Setup

Phantom	TSL, Measured Date	Probe, Calibration Date	DAE, Calibration Date
Twin-SAM V5.0 (30deg probe tilt) -	HBBL 5-10000MHz ,	EX3DV4 - SN7391, 2024-11-29	DAE4 Sn1495, 2024-07-24
1901			

Scan Setup

	Area Scan	Zoom Scan
Grid Extents [mm]	120.0 x 200.0	28.0 x 28.0 x 28.0
Grid Steps [mm]	10.0 x 10.0	5.0 x 5.0 x 1.4
Sensor Surface [mm]	3.0	1.4
Graded Grid	N/A	Yes
Grading Ratio	N/A	1.5
MAIA	Υ	Υ
Surface Detection	All points	VMS + 6p
Scan Method	Measured	Measured

	Area Scan	Zoom Scan
Date	2025-04-12	2025-04-12
psSAR1g [W/kg]	0.054	0.055
psSAR10g [W/kg]	0.023	0.022
Power Drift [dB]	-0.07	0.19
Power Scaling	Disabled	Disabled
Scaling Factor [dB]		
TSL Correction	No correction	No correction
M2/M1 [%]		71.0
Dist 3dB Peak [mm]		10.3

